

[All Products](#) / [Optics](#) / [Optical Mirrors](#) / [Flat Mirrors](#) / [Laser Mirrors](#)

Extreme Ultraviolet (EUV) Flat Mirrors



- Maximum Achievable Reflection at 13.5nm
- Designed for EUV Beam Steering and Harmonic Separation
- 5° and 45° AOI Versions Available

Common Specifications

Physical & Mechanical Properties			
Diameter (mm):	25.40 ±0.25	Back Surface:	Commercial Polish
Clear Aperture (%):	90	Edges:	Fine Ground
Parallelism (arcmin):	3	Surface Roughness (Å):	<5 RMS
Thickness (mm):	6.35 ±0.508		
Optical Properties			
Surface Flatness (P-V):	λ/10 @ 632.8nm		
Substrate:	Single Crystal Silicon	Surface Quality:	10-5
Coating:	Mo/Si Multilayer Top Layer: Silicon	Coating Type:	Metal/Semiconductor
Design Wavelength DWL (nm):	13.5		
Electrical			
Center Energy (eV):	92		

Technical Information

Products

Dia. (mm)	Coating Specification	Coating	AOI (°)	Thickness (mm)	Stock Number	Price	Buy
25.40	R _{abs} >60% @ 13.5nm, 5° (s-pol)	Mo/Si Multilayer Top Layer: Silicon	5	6.35	#38-759	€2.595,60	5 In Stock
25.40	R _{abs} >65% @ 13.5nm, 45° (s-pol)	Mo/Si Multilayer Top Layer: Silicon	45	6.35	#38-760	€2.595,60	20+ In Stock



Copyright 2025 | Edmund Optics BV, De Maas 22B, 5684 PL Best, The Netherlands
Phone: 1-800-363-1992 :
www.edmundoptics.com